

Supporting Information

in situ XAFS studies for Sulfurization of CeO₂ by SO₂

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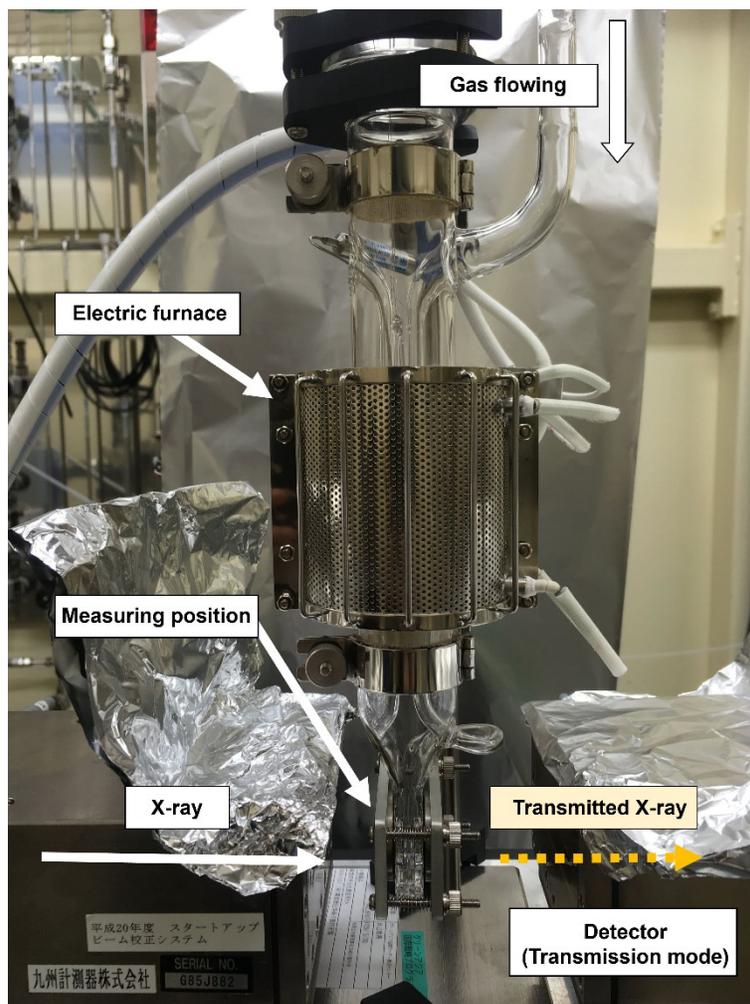


Figure S1(a). Image of a glass cell of *in situ* measurements (Transmission mode)

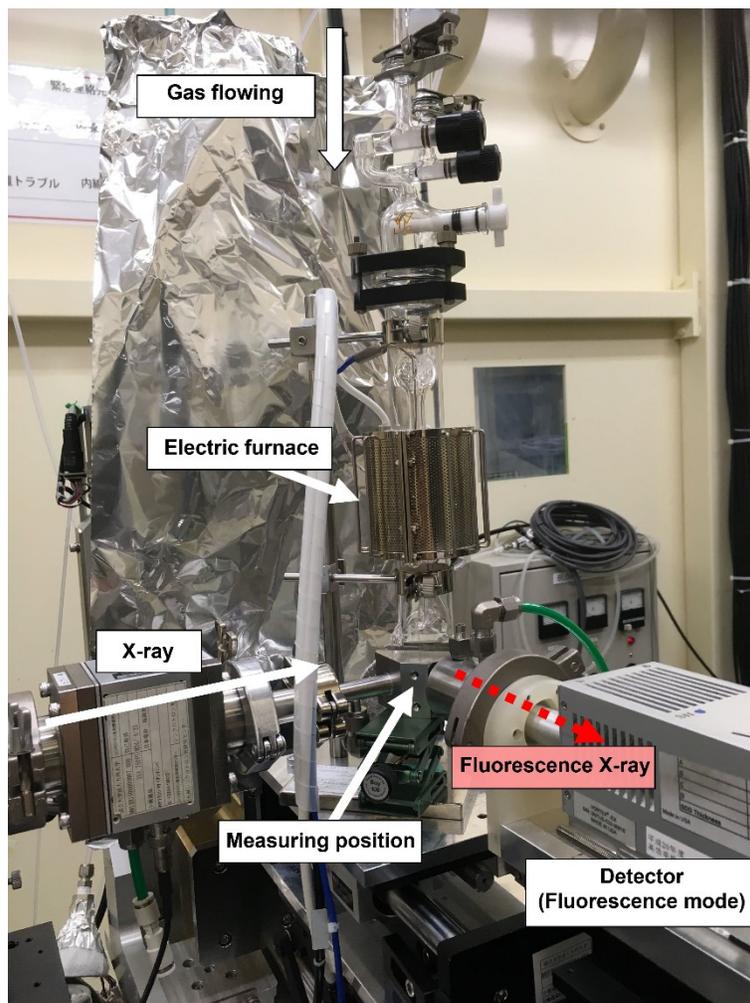


Figure S1(b). Image of a glass cell of *in situ* measurements (Fluorescence mode)

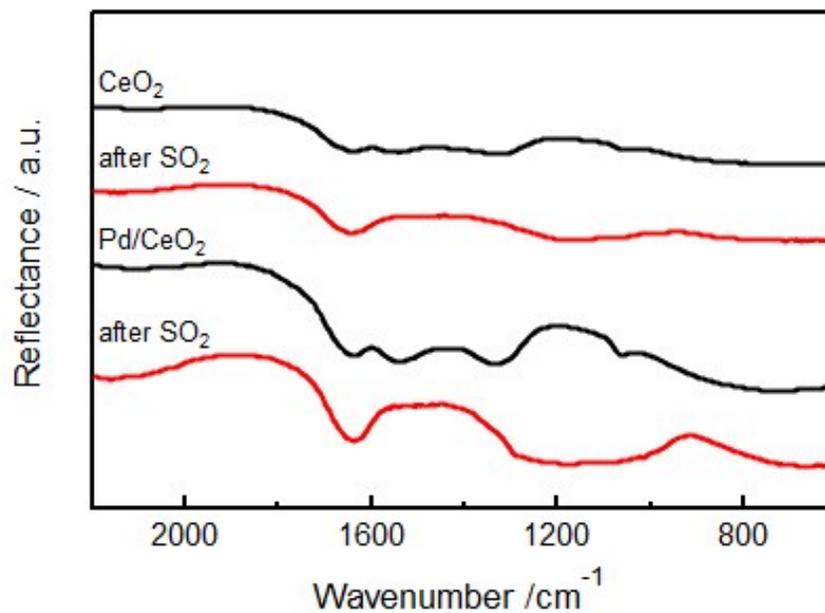


Figure S2. Diffuse reflectance FTIR spectra of CeO₂ and Pd/CeO₂

The black traces correspond to the fresh samples, while the red traces represent the samples after 300 min of exposure to 500 ppm SO₂ in N₂ at 500 °C.

The spectra were obtained at room temperature with a resolution of 4 cm⁻¹.